Notice of References Cited

Application/Control No.

Applicant(s)/Patent Under Reexamination YUEH ET AL.

Examiner

Amanda C Walke

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,391,518	05-2002	Jung et al.	430/270.1
	В	US-2003/0219678	11-2003	Harada et al.	430/270.1
	С	US-6,800,418	10-2004	Yoon et al.	430/270.1
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	Н	US-		-	
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.